



512MB – 64Mx64 DDR2 SDRAM UNBUFFERED, SO-DIMM

FEATURES

- Unbuffered 200-pin, Small-Outline DIMM (SO-DIMM)
- Fast data transfer rates: PC2-5300*, PC2-4200 and PC2-3200
- Utilizes 667*, 533 and 400 MT/s DDR2 SDRAM components
- $V_{CC} = 1.8V \pm 0.1V$
- $V_{CCSPD} = 1.7V$ to 3.6V
- JEDEC standard 1.8V I/O (SSTL_18-compatible)
- Differential data strobe (DQS, DQS#) option
- Four-bit prefetch architecture
- DLL to align DQ and DQS transitions with CK
- Multiple internal device banks for concurrent operation
- Supports duplicate output strobe (RDQS/RDQS#)
- Programmable CAS# latency (CL): 3, 4, and 5*
- Adjustable data-output drive strength
- On-die termination (ODT)
- Serial Presence Detect (SPD) with EEPROM
- Auto & self refresh (64ms: 8,192 cycle refresh)
- Gold edge contacts
- RoHS Compliant
- JEDEC Package option
 - 200 Pin (SO-DIMM)
 - PCB – 30.00mm (1.181") TYP.

DESCRIPTION

The WV3HG64M64EEU is a 64Mx64 Double Data Rate 2 SDRAM memory module based on 512Mb DDR2 SDRAM components. The module consists of eight 64Mx8, in FBGA package mounted on a 200 pin SO-DIMM FR4 substrate.

* This product is under development, is not qualified or characterized and is subject to change or cancellation without notice.

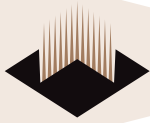
NOTE: Consult factory for availability of:

- Vendor source control options
- Industrial temperature option

OPERATING FREQUENCIES

	PC2-5300*	PC2-4200	PC2-3200
Clock Speed	333MHz	266MHz	200MHz
CL-tRCD-tRP	5-5-5	4-4-4	3-3-3

Note:
 • Consult factory for availability



PIN CONFIGURATION

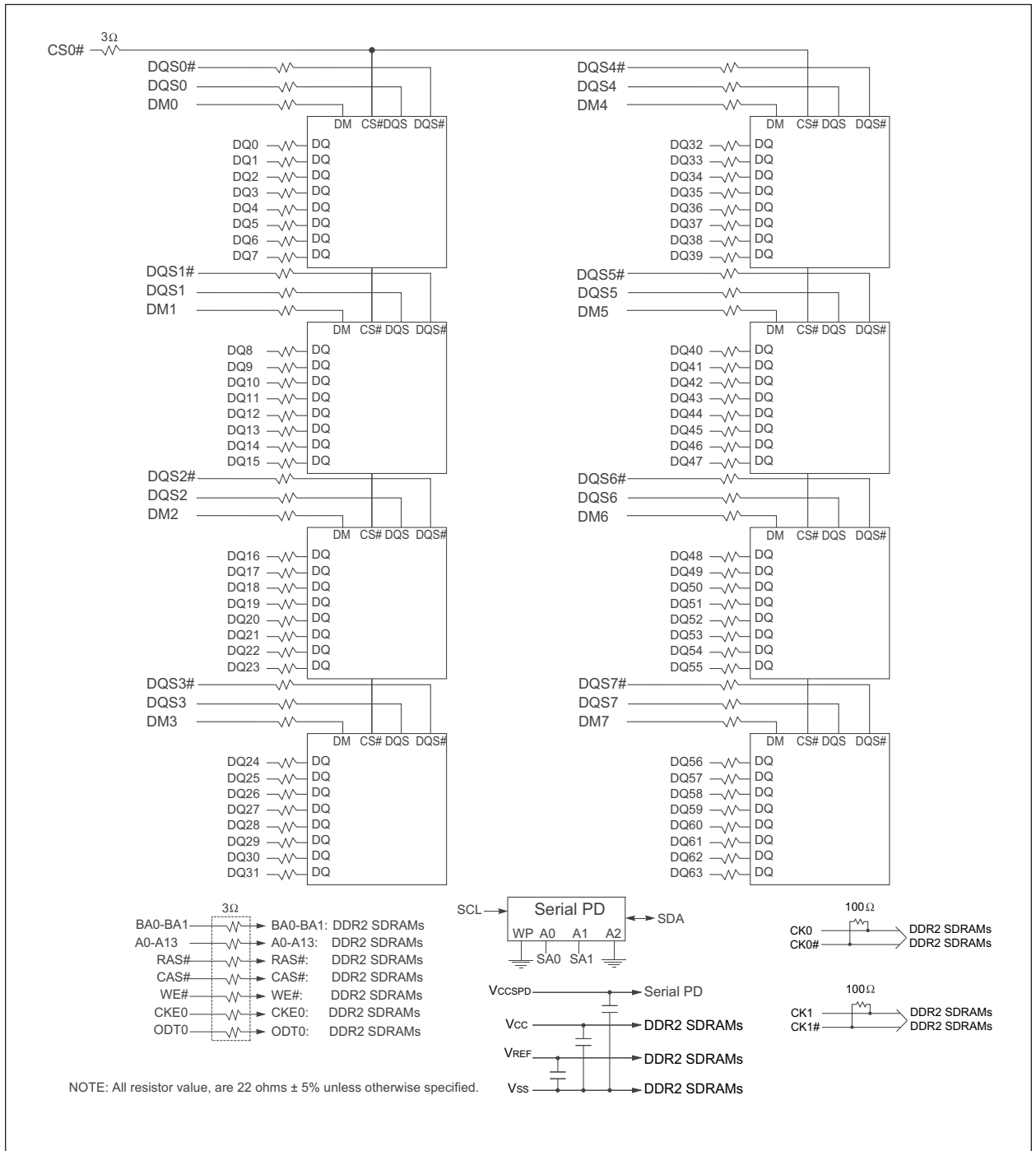
PIN#	SYMBOL	PIN#	SYMBOL	PIN#	SYMBOL	PIN#	SYMBOL
1	VREF	51	DQS2	101	A1	151	DQ42
2	Vss	52	DM2	102	A0	152	DQ46
3	Vss	53	Vss	103	vcc	153	DQ43
4	DQ4	54	Vss	104	vcc	154	DQ47
5	DQ0	55	DQ18	105	A10/AP	155	Vss
6	DQ5	56	DQ22	106	BA1	156	Vss
7	DQ1	57	DQ19	107	BA0	157	DQ48
8	Vss	58	DQ23	108	RAS#	158	DQ52
9	Vss	59	Vss	109	WE#	159	DQ49
10	DM0	60	Vss	110	CS0#	160	DQ53
11	DQS0#	61	DQ24	111	vcc	161	Vss
12	Vss	62	DQ28	112	vcc	162	Vss
13	DQS0	63	DQ25	113	CAS#	163	NC
14	DQ6	64	DQ29	114	ODT0	164	CK1
15	Vss	65	Vss	115	NC	165	Vss
16	DQ7	66	Vss	116	A13	166	CK1#
17	DQ2	67	DM3	117	vcc	167	DQS6#
18	Vss	68	DQS3#	118	vcc	168	Vss
19	DQ3	69	NC	119	NC	169	DQS6
20	DQ12	70	DQS3	120	NC	170	DM6
21	Vss	71	Vss	121	Vss	171	Vss
22	DQ13	72	Vss	122	Vss	172	Vss
23	DQ8	73	DQ26	123	DQ32	173	DQ50
24	Vss	74	DQ30	124	DQ36	174	DQ54
25	DQ9	75	DQ27	125	DQ33	175	DQ51
26	DM1	76	DQ31	126	DQ37	176	DQ55
27	Vss	77	Vss	127	Vss	177	Vss
28	Vss	78	Vss	128	Vss	178	Vss
29	DQS1#	79	CKE0	129	DQS4#	179	DQ56
30	CK0	80	NC	130	DM4	180	DQ60
31	DQS1	81	vcc	131	DQS4	181	DQ57
32	CK0#	82	vcc	132	Vss	182	DQ61
33	Vss	83	NC	133	Vss	183	Vss
34	Vss	84	NC	134	DQ38	184	Vss
35	DQ10	85	NC	135	DQ34	185	DM7
36	DQ14	86	NC	136	DQ39	186	DQS7#
37	DQ11	87	vcc	137	DQ35	187	Vss
38	DQ15	88	vcc	138	Vss	188	DQS7
39	Vss	89	A12	139	Vss	189	DQ58
40	Vss	90	A11	140	DQ44	190	Vss
41	Vss	91	A9	141	DQ40	191	DQ59
42	Vss	92	A7	142	DQ45	192	DQ62
43	DQ16	93	A8	143	DQ41	193	Vss
44	DQ20	94	A6	144	Vss	194	DQ63
45	DQ17	95	vcc	145	Vss	195	SDA
46	DQ21	96	vcc	146	DQS5#	196	Vss
47	Vss	97	A5	147	DM5	197	SCL
48	Vss	98	A4	148	DQS5	198	SA0
49	DQS2#	99	A3	149	Vss	199	VCCSPD
50	NC	100	A2	150	Vss	200	SA1

PIN NAMES

SYMBOL	DESCRIPTION
A0-A13	Address input
ODT0	On-Die Termination
CK0, CK0#	Differential Clock Inputs
CK1, CK1#	Differential Clock inputs
CKE0	Clock Enable input
CS0#	Chip select
RAS#, CAS#, WE#	Command Inputs
BA0, BA1	Bank Address Inputs
DM0-DM7	Input Data Mask
DQ0-DQ63	Data Input/Output
DQS0-DQS7 DQS0#-DQS7#	Data Strobe
SCL	Serial Clock for Presence Detect
SA0-SA1	Presence Detect Address Inputs
SDA	Serial Presence Detect Data
Vcc	Power Supply
VREF	Reference voltage
Vss	Ground
VCCSPD	Serial EEPROM Power Supply
NC	No Connect



FUNCTIONAL BLOCK DIAGRAM





ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Min	Max	Units	
V _{CC}	Voltage on V _{CC} pin relative to V _{SS}	-0.5	2.3	V	
V _{IN} , V _{OUT}	Voltage on any pin relative to V _{SS}	-0.5	2.3	V	
T _{STG}	Storage Temperature	-55	100	°C	
I _L	Input leakage current; Any input 0V<V _{IN} <V _{CC} ; V _{REF} input 0V<V _{IN} <0.95V; Other pins not under test = 0V	Command/Address, RAS#, CAS#, WE#	-80	80	µA
		CS#, CKE	-40	40	µA
		CK, CK#	-20	20	µA
		DM	-5	5	µA
I _{oz}	Output leakage current; 0V<V _{IN} <V _{CC} ; DQs and ODT are disable	-5	5	µA	
I _{VREF}	V _{REF} leakage current; V _{REF} = Valid V _{REF} level	-16	16	µA	

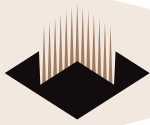
DC OPERATING CONDITIONS

All voltages referenced to V_{SS}

Parameter	Symbol	Rating			Units	Notes
		Min.	Type	Max.		
Supply Voltage	V _{CC}	1.7	1.8	1.9	V	
I/O Reference Voltage	V _{REF}	0.49 x V _{CC}	0.50 x V _{CC}	0.51 x V _{CC}	V	1
I/O Termination Voltage	V _{TT}	V _{REF} -0.04	V _{REF}	V _{REF} +0.04	V	2

Notes:

- V_{REF} is expected to equal V_{CC}/2 of the transmitting device and to track variations in the DC level of the same. Peak-to-peak noise on V_{REF} may not exceed +/-1percent of the DC value. Peak-to-peak AC noise on V_{REF} may not exceed +/-2 percent of V_{REF}. This measurement is to be taken at the nearest V_{REF} bypass capacitor.
- V_{TT} is not applied directly to the device. V_{TT} is a system supply for signal termination resistors, is expected to be set equal to V_{REF} and must track variations in the DC level of V_{REF}.



INPUT/OUTPUT CAPACITANCE

$T_A = 25^\circ\text{C}$, $f = 100\text{MHz}$

Parameter	Symbol	Min	Max	Units
Input Capacitance (A0~A13, BA0~BA1, RAS#, CAS#, WE#)	C_{IN1}	12	20	pF
Input Capacitance CKE0, ODT	C_{IN2}	12	20	pF
Input Capacitance CS0#	C_{IN3}	12	20	pF
Input Capacitance (CK0, CK0#, CK1, CK1#)	C_{IN4}	8	12	pF
Input Capacitance (DM0 ~ DM7), (DQS0 ~ DQS7)	C_{IN5} (667)	6.5	7.5	pF
	C_{IN5} (533)	6.5	8	pF
Input Capacitance (DQ0 ~ DQ63)	C_{OUT1} (667)	6.5	7.5	pF
	C_{OUT1} (533)	6.5	8	pF

Notes:

- AC specification is based on **SAMSUNG** components. Other DRAM manufactures specification may be different.

OPERATING TEMPERATURE CONDITION

Parameter	Symbol	Rating	Units	Notes
Operating temperature	TOPER	0° to 85°	°C	1, 2

Notes:

- Operating temperature is the case surface temperature on the center/top side of the DRAM. For the measurement conditions, please refer to JEDEC JESD51.2
- At 0°C - 85°C, operation temperature range, all DRAM specification will be supported.

INPUT DC LOGIC LEVEL

All voltages referenced to V_{SS}

Parameter	Symbol	Min	Max	Units
Input High (Logic 1) Voltage	$V_{IH}(DC)$	$V_{REF} + 0.125$	$V_{CC} + 0.300$	V
Input Low (Logic 0) Voltage	$V_{IL}(DC)$	-0.300	$V_{REF} - 0.125$	V

INPUT AC LOGIC LEVEL

All voltages referenced to V_{SS}

Parameter	Symbol	Min	Max	Units
Input High (Logic 1) Voltage DDR2-400 & DDR2-533	$V_{IH}(DC)$	$V_{REF} + 0.250$	-	V
Input Low (Logic 1) Voltage DDR2-667	$V_{IH}(DC)$	$V_{REF} + 0.200$	-	V
Input Low (Logic 0) Voltage DDR2-400 & DDR2-533	$V_{IL}(DC)$	-	$V_{REF} - 0.250$	V
Input Low (Logic 0) Voltage DDR2-667	$V_{IL}(DC)$	-	$V_{REF} - 0.200$	V



Icc SPECIFICATION

Symbol	Proposed Conditions	665	534	403	Units	
Icc0*	Operating one bank active-precharge; tCK = tCK(Icc), tRC = tRC(Icc), tRAS = tRAS min(Icc); CE is HIGH, CS# is HIGH between valid commands; Address bus inputs are SWITCHING; Data bus inputs are SWITCHING	680	640	640	mA	
Icc1*	Operating one bank active-read-precharge; I _{OUT} = 0mA; BL = 4, CL = CL(Icc), AL = 0; tCK = tCK(Icc), tRC = tRC(Icc), tRAS = tRAS min(Icc); CE is HIGH, CS# is HIGH between valid commands; Address bus inputs are SWITCHING; Data pattern is same as Icc4W	800	760	720	mA	
Icc2P**	Precharge power-down current; All banks idle; tCK = tCK(Icc); CE is LOW; Other control and address bus inputs are STABLE; Data bus inputs are FLOATING	64	64	64	mA	
Icc2Q**	Precharge quiet standby current; All banks idle; tCK = tCK(Icc); CE is HIGH, CS# is HIGH; Other control and address bus inputs are STABLE; Data bus inputs are FLOATING	280	240	240	mA	
Icc2N**	Precharge standby current; All banks idle; tCK = tCK(Icc); CE is HIGH, CS# is HIGH; Other control and address bus inputs are STABLE; Data bus inputs are SWITCHING	320	280	280	mA	
Icc3P**	Active power-down current; All banks open; tCK = tCK(Icc); CE is LOW; Other control and address bus inputs are STABLE; Data bus inputs are FLOATING	Fast PDN Exit MRS(12) = 0	240	280	240	mA
		Slow PDN Exit MRS(12) = 1	96	96	96	mA
Icc3N**	Active standby current; All banks open; tCK = tCK(Icc), tRC = tRC(Icc), tRAS = tRAS min(Icc); CE is HIGH, CS# is HIGH between valid commands; Other control and address bus inputs are SWITCHING; Data bus inputs are SWITCHING	440	400	400	mA	
Icc4W*	Operating burst write current; All banks open, Continuous burst writes; BL = 4, CL = CL(Icc), AL = 0; tCK = tCK(Icc), tRAS = tRAS max(Icc), tRP = tRP(Icc); CE is HIGH, CS# is HIGH between valid commands; Address bus inputs are SWITCHING; Data bus inputs are SWITCHING	1120	960	880	mA	
Icc4R*	Operating burst read current; All banks open, Continuous burst reads, I _{OUT} = 0mA; BL = 4, CL = CL(Icc), AL = 0; tCK = tCK(Icc), tRAS = tRAS max(Icc), tRP = tRP(Icc); CE is HIGH, CS# is HIGH between valid commands; Address bus inputs are SWITCHING; Data pattern is same as Icc4W	1160	1000	880	mA	
Icc5**	Burst auto refresh current; tCK = tCK(Icc); Refresh command at every tRFC(Icc) interval; CE is HIGH, CS# is HIGH between valid commands; Other control and address bus inputs are SWITCHING; Data bus inputs are SWITCHING	1200	1120	1120	mA	
Icc6**	Self refresh current; CK and CK# at 0V; CE 0.2V; Other control and address bus inputs are FLOATING; Data bus inputs are FLOATING	64	64	64	mA	
Icc7*	Operating bank interleave read current; All bank interleaving reads, I _{OUT} = 0mA; BL = 4, CL = CL(Icc), AL = tRC(Icc) - 1 * tCK(Icc); tCK = tCK(Icc), tRC = tRC(Icc), tRRD = tRRD(Icc), tRCD = 1 * tCK(Icc); CE is HIGH, CS# is HIGH between valid commands; Address bus inputs are STABLE during DESELECTs; Data bus inputs are SWITCHING.	1760	1760	1760	mA	

Icc specification is based on **SAMSUNG** components. Other DRAM manufactures specification may be different.

Note:

*: Value calculated as one module rank in this operating condition, and all other module ranks in IDD2P (CE LOW) mode.

** : Value calculated reflects all module ranks in this operating condition.



AC TIMING PARAMETERS & SPECIFICATIONS

AC CHARACTERISTICS			665		534		403		
PARAMETER		SYMBOL	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
Data	CL = 5	t _{CK (5)}	3,000	8,000					ps
	CL = 4	t _{CK (4)}	3,750	8,000	3,750	8,000	5,000	8,000	ps
	CL = 3	t _{CK (3)}	5,000	8,000	5,000	8,000	5,000	8,000	ps
	CK high-level width	t _{CH}	0.45	0.55	0.45	0.55	0.45	0.55	t _{CK}
	CK low-level width	t _{CL}	0.45	0.55	0.45	0.55	0.45	0.55	t _{CK}
	Half clock period	t _{HP}	MIN (t _{CH} , t _{CL})		MIN (t _{CH} , t _{CL})		MIN (t _{CH} , t _{CL})		ps
	Clock jitter	t _{JIT}		250		250		250	ps
Data	DQ output access time from CK/CK#	t _{AC}	-450	+450	-500	+500	-600	+600	ps
	Data-out high-impedance window from CK/CK#	t _{HZ}		t _{AC} MAX		t _{AC} MAX		t _{AC} MAX	ps
	Data-out low-impedance window from CK/CK#	t _{LZ}	t _{AC} MIN	t _{AC} MAX	t _{AC} MIN	t _{AC} MAX	t _{AC} MIN	t _{AC} MAX	ps
	DQ and DM input setup time relative to DQS	t _{DS}	100		100		150		ps
	DQ and DM input hold time relative to DQS	t _{DH}	225		225		275		ps
	DQ and DM input pulse width (for each input)	t _{DLPW}	0.35		0.35		0.35		t _{CK}
	Data hold skew factor	t _{QHS}		340		400		450	ps
	DQ...DQS hold, DQS to first DQ to go nonvalid, per access	t _{QH}	t _{HP} - t _{QHS}		t _{HP} - t _{QHS}		t _{HP} - t _{QHS}		ps
	Data valid output window (DVW)	t _{DVW}	t _{QH} - t _{DQSQ}		t _{QH} - t _{DQSQ}		t _{QH} - t _{DQSQ}		ns
Data Strobe	DQS input high pulse width	t _{DQSH}	0.35		0.35		0.35		t _{CK}
	DQS input low pulse width	t _{DQSL}	0.35		0.35		0.35		t _{CK}
	DQS output access time from CK/CK#	t _{DQSCK}	-400	+400	-450	+450	-500	+500	ps
	DQS falling edge to CK rising ... setup time	t _{DSS}	0.2		0.2		0.2		t _{CK}
	DQS falling edge from CK rising ... hold time	t _{DSH}	0.2		0.2		0.2		t _{CK}
	DQS...DQ skew, DQS to last DQ valid, per group, per access	t _{DQSQ}		240		300		350	ps
	DQS read preamble	t _{RPRE}	0.9	1.1	0.9	1.1	0.9	1.1	t _{CK}
	DQS read postamble	t _{RPST}	0.4	0.6	0.4	0.6	0.4	0.6	t _{CK}
	DQS write preamble setup time	t _{WPRES}	0		0		0		ps
	DQS write preamble	t _{WPRE}	0.35		0.35		0.35		t _{CK}
	DQS write postamble	t _{WPST}	0.4	0.6	0.4	0.6	0.4	0.6	t _{CK}
	Write command to first DQS latching transition	t _{DQSS}	WL - 0.25	WL + 0.25	WL - 0.25	WL + 0.25	WL - 0.25	WL + 0.25	t _{CK}
	Address and control input pulse width for each input	t _{IPW}	0.6		0.6		0.6		t _{CK}
	Address and control input setup time	t _{IS}	200		250		350		ps
	Address and control input hold time	t _{IH}	275		375		475		ps
	Address and control input hold time	t _{CCD}	2		2		2		t _{CK}

Note:
 AC specification is based on **SAMSUNG** components. Other DRAM manufactures specification may be different.
 Continued on next page



AC TIMING PARAMETERS (cont'd)

AC CHARACTERISTICS			665		534		403		
PARAMETER		SYMBOL	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
Command and Address	ACTIVE to ACTIVE (same bank) command	tRC	55		60		65		ns
	ACTIVE bank a to ACTIVE bank b command	tRRD	7.5		7.5		7.5		ns
	ACTIVE to READ or WRITE delay	tRCD	15		15		15		ns
	Four Bank Activate period	tFAW	37.5	37.5	37.5	37.5	37.5	37.5	ns
	ACTIVE to PRECHARGE command	tRAS	45	70,000	45	70,000	45	70,000	ns
	Internal READ to precharge command delay	tRTP	7.5		7.5		7.5		ns
	Write recovery time	tWR	15		15		15		ns
	Auto precharge write recovery + precharge time	tDAL	tWR + tRP		tWR + tRP		tWR + tRP		ns
	Internal WRITE to READ command delay	tWTR	7.5		7.5		10		ns
	PRECHARGE command period	tRP	15		15		15		ns
	PRECHARGE ALL command period	tRPA	tRP+tCK		tRP+tCK		tRP+tCK		ns
	LOAD MODE command cycle time	tMRD	2		2		2		tCK
	CKE low to CK,CK# uncertainty	tDELAY	tIS + tCK + tIH		tIS + tCK + tIH		tIS + tCK + tIH		ns
Self Refresh	REFRESH to Active of Refresh to Refresh command interfal	tRFC	105	70,000	105	70,000	105	70,000	ns
	Average periodic refresh interval	tREFI		7.8		7.8		7.8	µs
	Exit self refresh to non-READ command	tXSNR	tRFC (MIN) + 10		tRFC (MIN) + 10		tRFC (MIN) + 10		ns
	Exit self refresh to READ command	tXSRD	200		200		200		tCK
	Exit self refresh timing reference	tISXR	tIS		tIS		tIS		ps
ODT	ODT turn-on delay	tAOND	2	2	2	2	2	2	tCK
	ODT turn-on	tAON	tAC (MIN)	tAC (MAX) + 1000	tAC (MIN)	tAC (MAX) + 1000	tAC (MIN)	tAC (MAX) + 1000	ps
	ODT turn-off delay	tAOFD	2.5	2.5	2.5	2.5	2.5	2.5	tCK
	ODT turn-off	tAOF	tAC (MIN)	tAC (MAX) + 600	tAC (MIN)	tAC (MAX) + 600	tAC (MIN)	tAC (MAX) + 600	ps
	ODT turn-on (power-down mode)	tAONPD	tAC (MIN) + 2000	2 x tCK + tAC (MAX) + 1000	tAC (MIN) + 2000	2 x tCK + tAC (MAX) + 1000	tAC (MIN) + 2000	2 x tCK + tAC (MAX) + 1000	ps
	ODT turn-off (power-down mode)	tAOPD	tAC (MIN) + 2000	2.5 x tCK + tAC (MAX) + 1000	tAC (MIN) + 2000	2.5 x tCK + tAC (MAX) + 1000	tAC (MIN) + 2000	2.5 x tCK + tAC (MAX) + 1000	ps
	ODT to power-down entry latency	tANPD	3		3		3		tCK
	ODT power-down exit latency	tAXPD	8		8		8		tCK
Power-Down	Exit active power-down to READ command, MR[bit12=0]	tXARD	2		2		2		tCK
	Exit active power-down to READ command, MR[bit12=1]	tXARDS	7 - AL		6 - AL		6 - AL		tCK
	A Exit precharge power-down to any non-READ command.	tXP	2		2		2		tCK
	CKE minimum high/low time	tCKE	3		3		3		tCK

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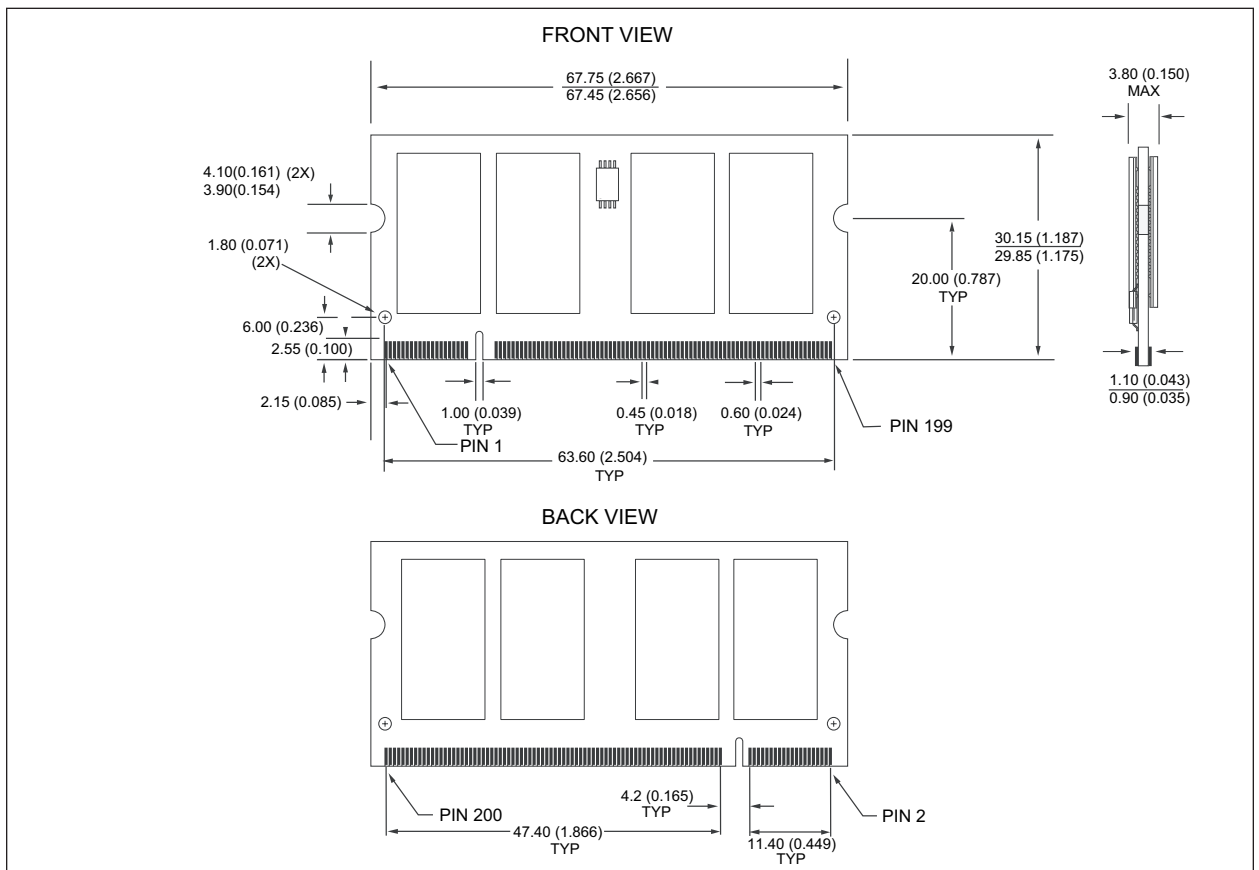
ORDERING INFORMATION FOR D4

Part Number	Clock/Data Rate Frequency	CAS Latency	t _{RCD}	t _{RP}	Height**
WV3HG64M64EEU665D4xxG*	333MHz/667Mb/s	5	5	5	30.00mm (1.181") TYP
WV3HG64M64EEU534D4xxG	266MHz/533Mb/s	4	4	4	30.00mm (1.181") TYP
WV3HG64M64EEU403D4xxG	200MHz/400Mb/s	3	3	3	30.00mm (1.181") TYP

* Consult Factory for availability

- NOTES:
- RoHS product. ("G" = RoHS Compliant)
 - Vendor specific part numbers are used to provide memory components source control. The place holder for this is shown as lower case "x" in the part numbers above and is to be replaced with the respective vendors code. Consult factory for qualified sourcing options. (M = Micron, S = Samsung & consult factory for others)
 - Consult factory for availability of industrial temperature (-40°C to 85°C) option

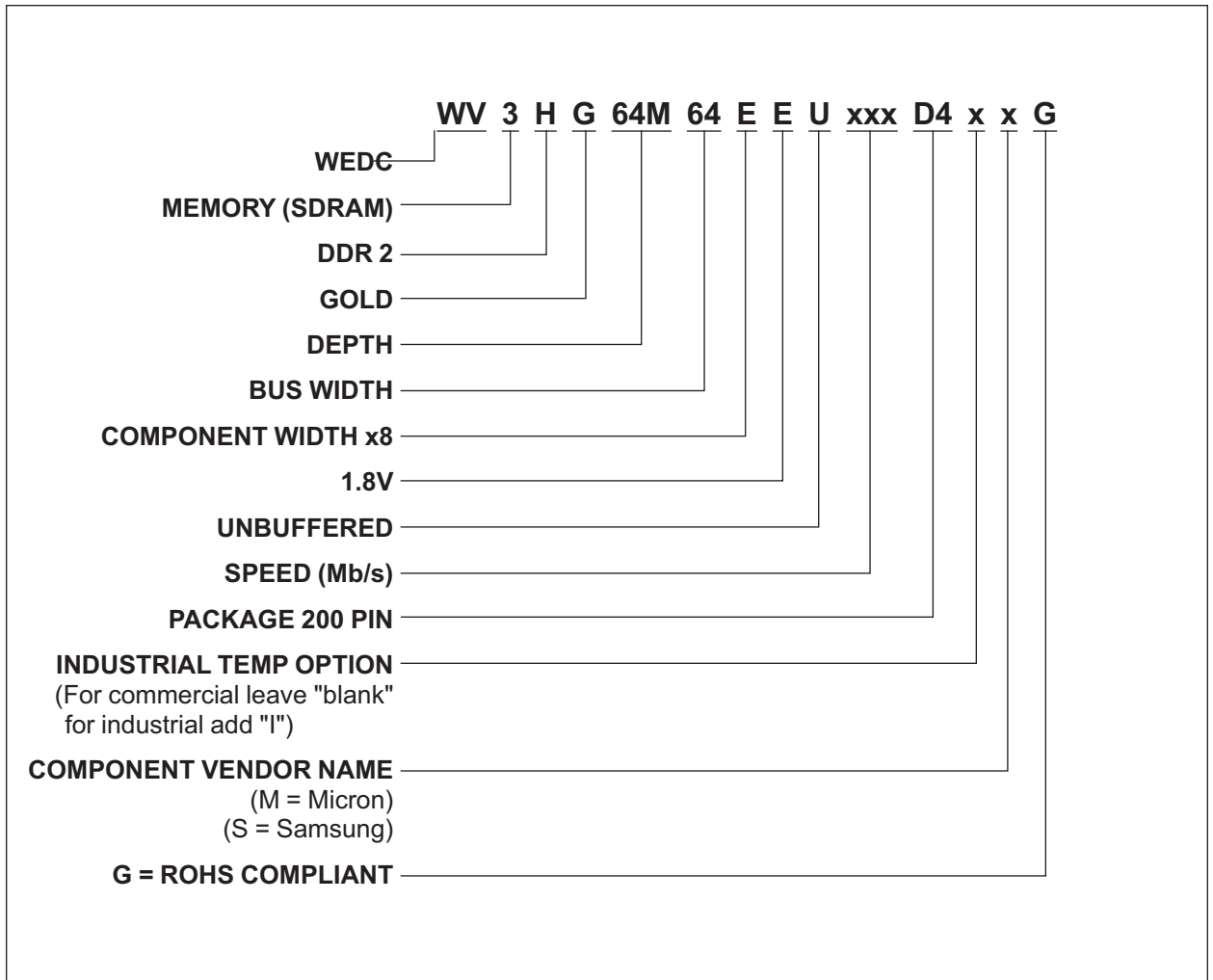
PACKAGE DIMENSIONS FOR D4

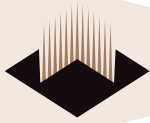


** ALL DIMENSIONS ARE IN MILLIMETERS AND (INCHES)



PART NUMBERING GUIDE



**Document Title**

512MB – 64Mx64 DDR2 SDRAM UNBUFFERED

DRAM DIE OPTIONS:

- SAMSUNG: C-Die, will move to E-Die Q2'06
- MICRON: U37Y: B-Die

Revision History

Rev #	History	Release Date	Status
Rev 0	Created	January 2006	Advanced
Rev 1	1.0 Updated V _{CC} spec	February 2006	Advanced
Rev 2	2.1 Updated AC specs 2.2 Updated ordering information 2.3 Added industrial temp option on part numbering guide 2.4 Added die rev info	May 2006	Advanced